



Drexel University's Centralized Research Facilities
along with FEI, EDAX and TMC



present

Current Trends in Electron Microscopy and Microanalysis

April 14, 2010

Drexel University, Bossone Research Enterprise Center
3126 Market Street, Philadelphia, PA

8:30 am Registration and Coffee

Morning Session

Chair Dr. Edward Basgall, CRF Drexel

9:00 am Introduction/Greetings – Dr. Selçuk Güçeri, Dean College of Engineering, Drexel University

9:10 am Latest Advances in Analytical and High-Resolution TEM/STEM – Dr. Jan Ringnalda, FEI

9:40 am Measuring and cancelling stray magnetic fields for SEMs and TEMs – Bill Reid, TMC

10:10 am Coffee Break

10:30 am Phase Mapping for Energy Dispersive Spectroscopy: The Future of X-ray Mapping – Tara Nylese, EDAX

11:00 am Controlling floor vibration and its effect on high resolution electron microscopy – Bill Reid, TMC

11:30 am Nanocharacterization in the Centralized Research Facilities at Drexel University – Dr. Zhorro Nikolov, CRF Drexel

Noon Complimentary Lunch

1:00 pm CRF Lab Tours

Afternoon Session

Chair: Dr. Craig Johnson, CRF Drexel

2:00 pm Latest Advances in Focused Ion Beam and Extreme Resolution Scanning Electron Microscopy – Dr. Lucille Giannuzzi, FEI

2:30 pm On direct-writing methods for electrically contacting semiconductor and functional oxide nanowires – Dr. Jonathan Spanier, Drexel University

3:00 pm Coffee Break

3:20 pm Characterizing Thin-Film Photovoltaics with Electron Back-Scattered Diffraction – Tara Nylese, EDAX

3:50 pm Lights, Camera, Action: A Look into the Development and Applications of Ultrafast In Situ TEM – Dr. Mitra Taheri, Drexel University

Complimentary coffee and lunch will be provided. Free parking will be available to pre-registered guests. Please click [here](#) to register on the CRF website by March 31. Space is limited. For more information please contact Craig Johnson at (215) 895-5900 or cljohnson@coe.drexel.edu.

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